Application/Control No. O9/961,223 Notice of References Cited Application/Control No. O9/961,223 Examiner TAN Q NGUYEN Applicant(s)/Patent Under Reexamination CHEN, IEON C. Page 1 of 1

U.S. PATENT DOCUMENTS

	Document Number Date Name Classification						
*	'	Country Code-Number-Kind Code	MM-YYYY	Name	Classification		
	Α	US-4,404,639	09-1983	McGuire et al.	701/35		
	В	US-5,400,018	03-1995	Scholl et al.	340/10.3		
	С	US-5,506,772	04-1996	Kubozono et al.	701/29		
	D	US-5,541,840	07-1996	Gurne et al.	701/33		
	E	US-5,657,233	08-1997	Cherrington et al.	705/400		
	F	US-5,758,300	05-1998	Abe, Kunihiro	455/456		
	G	US-5,916,286	06-1999	Seashore et al.	701/29		
	Н	US-6,263,265	07-2001	Fera, Gregory J.	701/19		
	1	US-6,330,499	12-2001	Chou et al.	701/33		
	J	US-					
	К	US-					
	L	US-					
	М	US-					
				<u> </u>			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification	
	N						
	0						
	Р						
	Q						
	R						
	s						
	Т						

NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)						
	U						
	٧						
	w						
	x	(C., MDFD c 707 05(a))					

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.



UNITED STATES DEFECTMENT OF COMMERCE Patent and Trademark Office

Address: ASSISTANT COMMISSIONER FOR PATENTS

Washington, D.C. 20231

APPLICATION NO./	FILING DATE	FIRST NAMED INVENTOR /	ATTORNEY DOCKET NO.
CONTROL NO.		PATENT IN REEXAMINATION	

EXAMINER

ART UNIT PAPER

4

DATE MAILED:

Please find below and/or attached an Office communication concerning this application or proceeding.

Commissioner of Patents and Trademarks

TAN Q NGUYE Primary Examin

Art Unit: 3661